

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/768,612 | Applicant(s)/Patent Under Reexamination LI ET AL. | |
| | Examiner Walter L. Lindsay, Jr. | Art Unit 2812 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| 1 | A | US-5,936,285 | 08-1999 | Pasch et al. | 257/368 |
| + | B | US-6,270,573 | 08-2001 | Kitabatake et al. | 257/E29.061 |
| + | C | US-6,596,080 | 07-2003 | Kawahara et al. | 117/106 |
| + | D | US-6,611,085 | 08-2003 | Gee et al. | 313/271 |
| + | E | US-6,734,453 | 05-2004 | Atanackovic et al. | 257/19 |
| + | F | US-6,743,680 | 06-2004 | Yu, Bin | 438/285 |
| + | G | US-6,753,266 | 06-2004 | Lukanc et al. | 438/739 |
| + | H | US-6,787,793 | 09-2004 | Yoshida, Akira | 257/19 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.